### IRIS: Infra-Red, in situ Non-destructive, in-circuit verification of silicon



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### "Non-destructive In-circuit Verification of Silicon"







### **Problem Statement:**

I want to control my data.

My data is in my hardware.

Therefore, I need to trust my hardware.



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...how can I trust my hardware?



### Trust Issues: Concerns About "The Supply Chain"



### The supply side gets all the political attention...



- Look at all those flags we don't recognize/trust!
- OMG did you say gray market!
- Wait ... so many jobs not in our country!
- [COUNTRY NAME] FIRST!!!
  - Cue billions in subsidies and political shenanigans



### ...but the distribution side is just as problematic!



- In software, we never trust the CDN
  - Would you download software over unencrypted http?
  - ...yet we instinctively trust unauthenticated couriers?
- "Any tourist" can buy, modify, return products
- Distributors aren't security experts

### The Big Problem: You Can't "Hash" Hardware

• There is no convenient, easyto-use method to confirm the correctness of hardware immediately before its use

 Hardware is one big "Time of Check versus Time of Use" (TOCTOU) problem!



\* This does not exist for hardware



### **SEM Analysis is Destructive**

- SEM can analyze a chip to the transistor level
- Requires cross-sectioning the chip for the beam to reach internal layers
- Can't check and use a specific chip





### Alternatives Exist, but...

- "Ptychographic X-Ray Imaging" to the rescue?
  - Non-destructive
  - 3D imaging of complex chips
  - Great for reverse engineering and design verification



Figure 2.] PXCT of detector ASIC chips a, 3D rendering of the PCXT tomogram with identified elements. The yellow triangle indicates a manufacturing fault in the Ti layer. The Al layer in the region of the red triangle shows variances in thickness causing a waveness of the Ti layer on top. Via, through-layer connector, **b**, Axial section across the second lowest layer, which contains the transistor gates; the grey scale (top right) represents electron density (in  $e^-\lambda^{-1}$ ). The corresponding layer from the design file is shown as the partial overlay in yellow.

#### https://www.nature.com/articles/nature21698



# ...They Require a Building-Sized Microscope



#### https://www.psi.ch/en/sls/about-sls



### **Problem Statement:**

I want to control my data.

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Therefore, I need to trust my hardware.





### **Define the Threat Model**



### **Assumption: The Threat Is the Supply Chain**



- "Is it Hackable?" is different from "Has it been modified?"
  - "Can I trust this piece of hardware" as-delivered is the question for this talk
- Thus:
  - "Can this piece of hardware resist arbitrary probing" after theft/seizure is *not*-in-scope
  - In my opinion, you can't win that game anyways...

### Unpacking the Supply Chain Threat Model by Analogy

#### Can I trust this chip?



Is this safe to eat?



### Limitations of the Analogy



- Stakes:
  - A modified chip in a server could impact millions of users
- Remedies:
  - Chips are made in billiondollar fabs

- Stakes:
  - A poisoned fruit might make the person who ate it sick
- Remedies:
  - Fruit grows on trees

However, both require global supply chains...



...and we verify our chips about as much as we verify our fruit.

### Level O: Detectable at Home (Point of Use) Exemplar: Misrepresentation of Goods

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### Level 1: Easily Detected With \$1k-\$10k Tools "Block-Level Modifications"



4. Function Block Diagram





### **Examplar: Modified NIC Chip**







- NIC blocks available now as F/OSS or low-cost IP
- Uses older process (~65nm)
- Estimate <\$300k up-front cost to mount attack
- Unit cost is possibly even profitable

### Level 2: Detected With \$10k-\$100k tools Sub-block RTL-Level Modifications







https://github.com/openhwgroup/cva6?tab=readme-ov-file

### **Key Assumptions**

- Assumption: there are two versions of the chip in the supply chain, one with the modification, and one without
  - "Bad by design" is a different question
  - https://ghostwriteattack.com/ riscvuzz.pdf





https://github.com/openhwgroup/cva6?tab=readme-ov-file

### **Exemplar: Modifying a CPU Pipeline**

- Observation:
  - ra (x1) on RISC-V is the link register
  - Compiled code only uses it in limited contexts, e.g.: "jalr, ra target"
- Create a memory protection bypass with trigger using this primitive

ffd0381e <x< th=""><th>ous_kernel::arch::ri</th><th>scv::current_pid&gt;:</th></x<>	ous_kernel::arch::ri	scv::current_pid>:
ffd0381e:	1141	addi sp,sp,-16
ffd03820:	c606	sw ra,12(sp)
ffd03822:	0000f097	auipc ra,0xf
ffd03826:	db4080e7	jalr -588(ra) # ffd125d6 <read_satp></read_satp>
ffd0382a:	8159	srli a0,a0,0x16
ffd0382c:	0ff57593	zext.b a1,a0
ffd03830:	c581	<pre>beqz a1,ffd03838 <xous_kernel::arch::riscv::curre< pre=""></xous_kernel::arch::riscv::curre<></pre>
ffd03832:	40b2	lw ra,12(sp)
ffd03834:	0141	addi sp,sp,16
ffd03836:	8082	ret
ffd03838:	ffd15537	lui a0,0xffd15
ffd0383c:	a2450513	addi a0,a0,-1500 # ffd14a24 <_ebss+0xfff91d64>
ffd03840:	0000d097	auipc ra, 0xd
ffd03844:	01a080e7	<pre>jalr 26(ra) # ffd1085a <core::option::unwrap_failed></core::option::unwrap_failed></pre>



# **Exemplar: Modifying a CPU Pipeline**

- Hypothetical Trojan:
  - Decoding a "load" using ra as the address base...
  - ...causes ra contents to be treated as if a physical address
  - Thus bypassing virtual memory protection
  - Optional:
    - Use unlock "knock" sequence to frustrate discovery by fuzzing
    - i.e. sequence is armed by a preceding "dummy" instruction like "addi x0, x0, 0x666"
  - Requires O(10)-O(100) logic cells to implement





### Level 3: Requires \$1mm+ Tools/Novel Techniques Exemplar: Tailored Mask Edits







### Exemplar: Reduced Round Cryptography Using a Small Mask Edit



- Some ciphers use repeated round of computation for security
  - Instead of implementing N copies of the hardware...
  - ...a single round is implemented in a loop

### Background: Multi-Round Cipher



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Round "0"

Load in fresh data

0000 - load 0001 - round 0010 - round 0011 - round 0100 - round 0101 - round 0110 - round 0111 - round 1000 - round 1001 - round 1010 - round 1011 - round 1011 - round

- 1101 round
- 1110 round
- 1111 hold

### Background: Multi-Round Cipher



Rounds "1..(n-1)"
Repeatedly apply the round function to the data



### Background: Multi-Round Cipher



Round "n"

Hold the result for read-out

0000 - load 0001 - round 0010 - round 0011 - round 0100 - round 0101 - round0110 - round 0111 - round1000 - round1001 - round 1010 - round 1011 - round 1100 - round 1101 - round 1110 - round 1111 - hold



### The Attack



- What if you tied the upper bits of the "holding register" selection input together?
  - 000<mark>0 load</mark>
  - 0001 round
  - 0010 round
  - 0011 round
  - **010**0 round
  - 0101 round
  - 0110 round
  - **0111** round
  - 1000 round
  - 1001 round
  - **101**0 round
  - **101**1 round
  - **110**0 round
  - 1101 round
  - **111**0 round
  - **111**1 hold

### The Attack



What if you tied the upper bits of the "holding register" selection input together?

> 0000 - load 0001 - round 1110 - round 1111 - hold 0000 - load 0001 - round 1110 - round 1111 - hold 0000 - load 0001 - round 1110 - round 1110 - round 1111 - hold 0000 - load

> > - round

0 – round

– hold

Only 2 rounds matter! • But! Timing side channel and power side channel looks "as if" the full rounds happened



### The Attack

- Why it's sneaky:
  - Symmetric reduction of rounds -> decryption/encryption works "fine"
  - Sidechannels same or very similar
  - Reduced-round variants still have reasonable bulk statistics
  - If secret key is truly kept secret inside the chip...
    - ...Detection requires
       cryptanalysis of ciphertext
- Why it's hard to detect:
  - Maybe just a via-only change!

### **Threat Model Recap**



Level 3: Detected only with \$1mm+ tools and/or requires new techniques

Level 2: Detected with \$10k-\$100k tools

Level 1: Detected with \$1k-\$10k tools

Level 0: Detected with <\$1k tools



- Level 3: maybe destructive analysis required???
- Level 2: academic papers
- Level 1: practiced by targeted industries
- Level 0: routinely practiced



### In Practice, Nobody is Checking



### Nobody is checking

- The general public does not check chips beyond Level 0
  - Public companies that do check also do not disclose problems
  - Disclosing supply chain issues is bad for business
- Threat actors have broad latitude to operate without consequence

A few people are checking



### This Work: Infra Red, *in situ* (IRIS)



#### Academics & agencies

**Targeted Industries** 

Point of Use (at-home)

- Reduce detection barrier by an order of magnitude
  - Increase the capability of athome detection by at least one level
  - Improve trust in hardware for everyday people



### Introducing IRIS: Infra-Red, *in situ* Verification of Silicon



- A method for inspecting certain types of chips
- After they are attached to a circuit board
- Without damage



### What Type of Chips?





- Short answer: "The shiny ones"
  - WLCSP or FCBGA types of packages
  - Exposed silicon back with no film or paint applied
  - Ideally polished and/or thinned
  - P- (lightly) doped substrate
    - TSMC-like foundry
    - P+ doped substrate (Intel, SMIC?) scatters light too much
- Does not work for chips in plastic packages
  - Manufacturer must "design for inspectability"

### How it Works: Silicon is Transparent to Infrared Light





### Silicon is Transparent to Infrared Light



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### Some CMOS Cameras are Sensitive to IR (e.g.: Sony Starvis2 → Surveillance Market)

#### FSM-IMX678C (Color):



visible infrared

#### SONY

#### Comparison Image under 0.2 lux

Gain setting of IMX334 is 4times of IM00578, however they can get same output brightness.



MX334 Condition: F1.6, exposure time 33.3 ms, gain 60 dB

Condition: F1.6, exposure time 33.3 ms, gain 48 dB

INDOITS-AAOR

#### Comparison Image under NIR at 850 nm



IMX334 Condition: F1.6, exposure time 33.3 ms, gain 0 dB IMD/678 Condition: F1.6, exposure time 33.3 ms, gain 0 dB

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### **Putting it All Together: IRIS**



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Inspection of chips from the back side After they have been assembled into a product

### **Prior Work**

Key Extraction Using Thermal Laser Stimulation



Figure 7: Overview reflected light image of the Xilinx Ultrascale XCKU040 die. The area containing the configuration and decryption logic is highlighted.  "Key Extraction Using Thermal Laser Stimulation"

- Lohrke et al CHES 2018 (via Dimitry Nedospasov)
- Hamamatsu Phemos-1000

### Fritzchens Fritz flickr feed

Backside IR imaging with CMOS camera



#### CC BY2.5 Cepheiden via wikipedia



#### FRONTSIDE



### Why Backside?

- The backside metal is closest to the transistors
- Topside metal tends to be just regular arrays for power distribution + pads





#### BACKSIDE

# **IRIS Implementations**





~EUR5000, fully automatic adjustments



#### <EUR300 fully manual adjustments

### Manual Adjustment



- Possible to generate high quality images
- Fussy to set up
- Repeatability issues
- Useful for end-user verification setups
  - Lower cost
  - More effort, but used rarely only when new chips are acquired



### **Automated Adjustment**

- <10 micron precision repeatability</p>
- Fully automated X/Y/Z positioning
- Fully automated light positioning
- Good repeatability
- Useful for
  - Generating reference images
    - Higher quality images used as comparison point for end users
  - Higher throughput screening
  - Higher confidence measurements





### Automated Platform: Jubilee

- Developed by Prof Nadya Peek's laboratory
- Open source, 3D motion
   platform
- Kinematically coupled Z-stage
- https:// machineagency.github.io/ science\_jubilee/





### **Microscope** Core



- Chip surface is parallel to X-Y plane
- Positive X is towards the right
- Positive Y is towards the bottom
- Increazing Z moves the chip farther from the camera

# Chip Features vs. Angle of Incident Light





### Nanometer-Precision Fine Focus Stage For <\$200





3x piezo actuators

- Originally used for automotive haptics
- Kinematic coupling
  - Glass hemisphere into Vgroove
    - "Exactly constrained" design
  - Sub-micron repeatability of stage removal



**Imaging Software** 

- Autofocus
- Auto step and repeat
- https://github.com/bunnie/jubiris/



### Focus Convergence



 Better than +/-5um on average versus ideal plane

- Within depth of field limit for 10x objective
- <10 seconds per image step</li>
  - Depends heavily on environmental vibrations
- Some divergence due to top markings





### Semi-Automated **Image Stitching**

Sampled images do not perfectly align due to machine tolerances

Sand Schweise Intel Statute of State families and these



### **Template Stitch + MSE Cleanup**

- Stitch ~200 images in about 10-15 minutes
- Some manual cleanup needed
- Everything in IRIS in open source and documented with blog posts



https://bunnie.org/iris



### **IRIS Examples**

https://siliconpr0n.org/archive/ doku.php? id=tag:collection\_bunnie&do=showtag &tag=collection\_bunnie





### **IRIS Examples: Seeing Standard Cells**

AOI/

OAI

NOR/

NAND

FF

**BUF/INV** 



SKY130 process



### **More Standard Cells**



TSMC 22nm process, same scale as SKY130 on previous slide



# So, What Does IRIS Get Us?





### Level 1: Block-Level Modification

4. Function Block Diagram



 If chip in WLCSP package:
 Easy to "diff out" blocklevel modifications

 Would need reference images, possibly crowd-sourced



# Grounding a Hypothetical Trojan



### Hypothetical "Trojan":

- Records ~few kiB of network traffic
- Has a trigger
  - Say, respond to ICMP secret knock to exfiltrate data





3.8mm

### **Example of Block Sizes**





#### Estimated @ 65nm node



### Level 2: Small RTL Modifications



"Probably detectable"

- Naive RTL insertion would have place/route deviations
- Recall from earlier discussion:
  - 0(10)-0(100) cells added





### Limitations of Comparing IRIS Images



Logic gates show up as fuzzy blobs "by type of gate"

- In reality we can only know "how many gates"
- "Exactly what gates" may be spoofable

 An omnipotent adversary could "lock down" place/route paths to maintain net shape, logic cell types

 Would leave some trace, e.g. reduced timing margin, power consumption changes



### Related Work in Progress: Automated Gate Count Census



Design data (standard cell map)

Imaging data (arbitrary rotation & translation)

Aligned cell-to-image map



### **Quantifying Gate Counts**

	54		



Trying to train a CNN classifier to estimate gate count

- "G" plus/minus an uncertainty of "sigma"
  - Uncertainty due to noise, dirt, scratches, process variations...

 Bonus if it can classify types of logic cells



# Level 3: Targeted Mask Modifications



- No difference in images, by attacker's intention
  - Modifications solely on midlevel metal layers
  - No extra logic gates, but functionality is changed
    - "Spare cells" possibly used for malicious purposes





# **Next Steps: Hybrid Verification**

### Size Scale

### **Confidence of Verification**

#### Qualitative

- Memories
- Analog blocks
- I/O pads
- Logic regions

#### Quantitative

- Bits of memory
- · Amount of standard cells

#### Functional

- Wiring of logic
- Types of logic gates

More confident	1	Less confident		Full	
IRIS	+	Scan chain	=	IRIS + Scan chain	
Less		More			

# Chip

Circuit

### Even If We Can't Get to 100% Confidence: IRIS is Better than Just Trusting The Label



**2263** ~100MiB image of chip

>>



### Status Quo: "Just Trust the Label"



#### Threat actors operate in a zero-risk, zero-consequences scenario

#### Nobody is checking

A few people are checking



### Infra Red, *in situ* (IRIS): Improving Trust For Everyday People



Still some things we can't catch, but...

....IRIS could raise the bar

Even modest IRIS adoption may deter threat actors

- "Easier" hardware Trojans are no longer a zero-risk proposition
- Ideally, products are designed to facilitate inspection
  - This only happens if there is demand for inspectable products

Also, it's just fun to look inside chips!



# Demo / Q&A

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@bunniestudios.bsky.social

#### With thanks to:



Github sponsors:

Current sponsors 17

Past sponsors 30





### https://bunnie.org/iris

Self organized session Day 2 14:00-16:00 "Microscope Nerds and IC Die Photography Meetup" failOverflow (I6/H3Foyer) for a pointer